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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Takahiro Yamaguchi, et al.
Serial No.: 09/811,153
Filing Date: March 16, 2001
Title: Apparatus for and Method of
Measuring Jitter
Conf. No. 5797

Examiner: Dac V. Ha

Art Unit: 2634

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Technology Center 2600

September 3, 2004
San Francisco, California

Commissioner of Patents
P.O. Box 1450
Alexandra, VA 22313-1450

RESPONSE TO OFFICE ACTION

Sir:

This communication is submitted in response to the office action mailed June 21, 2004
(referred to herein as "Office Action").